BLS7G3135LS-200

LDMOS S-band radar power transistor

Rev. 2 — 23 September 2013

Product data sheet

1. Product profile

1.1 General description

200 W LDMOS power transistor for S-band radar applications in the frequency range from 3100 MHz to 3500 MHz.

Table 1. Typical performance

Typical RF performance at $T_{\rm case}$ = 25 °C; t_p = 300 μ s; δ = 10 %; $I_{\rm Dq}$ = 100 mA; in a class-AB production test circuit.

Test signal	f	V_{DS}	P_{L}	G_p	η_{D}	t _r	t _f
	(GHz)	(V)	(W)	(dB)	(%)	(ns)	(ns)
pulsed RF	3.1	32	200	12	48	8	6
	3.3	32	200	12	46	8	6
	3.5	32	200	12	43	8	6

1.2 Features and benefits

- High efficiency
- Excellent ruggedness
- Designed for broadband operation
- Excellent thermal stability
- Easy power control
- Integrated ESD protection
- High flexibility with respect to pulse formats
- Internally matched for ease of use (input and output)
- Compliant to Directive 2002/95/EC, regarding Restriction of Hazardous Substances (RoHS)

1.3 Applications

S-band radar applications in the frequency range 3100 MHz to 3500 MHz



2. Pinning information

Table 2. Pinning

Pin	Description		Simplified outline	Graphic symbol
1	drain			
2	gate		1 1	1
3	source	<u>[1]</u>		2 — 3 3 sym112

^[1] Connected to flange.

3. Ordering information

Table 3. Ordering information

Type number	Packag	ge	
	Name	Description	Version
BLS7G3135LS-200	-	earless flanged ceramic package; 2 leads	SOT502B

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Min	Max	Unit
V_{DS}	drain-source voltage	-	65	V
V_{GS}	gate-source voltage	-0.5	+13	V
T _{stg}	storage temperature	-65	+150	°C
Tj	junction temperature	<u>[1]</u> _	225	°C

^[1] Continuous use at maximum temperature will affect the reliability.

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Тур	Unit
$Z_{th(j\text{-}mb)} \text{ transient thermal impedance from junction}$	T_{case} = 85 °C; P_L = 200 W			
	to mounting base	t_p = 100 μ s; δ = 20 %	0.147	K/W
		t_p = 200 μ s; δ = 20 %	0.162	K/W
		t_p = 500 μ s; δ = 20 %	0.186	K/W

6. Characteristics

Table 6. DC characteristics

 $T_i = 25$ °C unless otherwise specified.

,	•					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{(BR)DSS} \\$	drain-source breakdown voltage	$V_{GS} = 0 \text{ V}; I_D = 2.7 \text{ mA}$	65	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$V_{DS} = 10 \text{ V};$ $I_{D} = 270 \text{ mA}$	1.5	1.9	2.3	V
I_{DSS}	drain leakage current	$V_{GS} = 0 \text{ V}; V_{DS} = 28 \text{ V}$	-	-	4.2	μΑ
I_{DSX}	drain cut-off current	$V_{GS} = V_{GS(th)} + 3.75 \text{ V}$	-	51	-	Α
I_{GSS}	gate leakage current	$V_{GS} = 11 \text{ V}; V_{DS} = 0 \text{ V}$	-	-	420	nA
9 _{fs}	forward transconductance	$V_{DS} = 10 \text{ V}; I_{D} = 2.7 \text{ A}$	-	2.34	-	S
R _{DS(on)}	drain-source on-state resistance	$V_{GS} = V_{GS(th)} + 3.75 \text{ V}$	-	0.06	-	Ω

Table 7. RF characteristics

Test signal: pulsed RF; t_p = 300 μ s; δ = 10 %; RF performance at V_{DS} = 32 V; I_{Dq} = 100 mA; T_{case} = 25 °C; unless otherwise specified, in a class-AB production test circuit.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Gp	power gain	$P_{L} = 200 \text{ W}$	8.8	12	-	dB
RLin	input return loss	$P_{L} = 200 \text{ W}$	-	-8	-4	dB
η_{D}	drain efficiency	$P_{L} = 200 \text{ W}$	38	43	-	%
P _{droop(pulse)}	pulse droop power	$P_{L} = 200 \text{ W}$		0.1	0.25	dB
t _r	rise time	$P_{L} = 200 \text{ W}$	-	8	50	ns
t _f	fall time	P _L = 200 W	-	6	50	ns

7. Test information

7.1 Ruggedness in class-AB operation

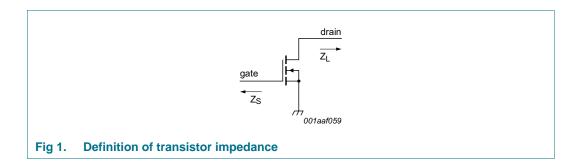
The BLS7G3135LS-200 is capable of withstanding a load mismatch corresponding to VSWR = 10 : 1 through all phases under the following conditions: V_{DS} = 32 V; I_{Dq} = 100 mA; P_L = 200 W; f = 3100 MHz; t_p = 300 μ s; δ = 10 %.

7.2 Impedance information

Table 8. Typical impedance

Measured load pull data; $V_{DS} = 32 \text{ V}$; $I_{Dq} = 100 \text{ mA}$; typical values unless otherwise specified.

f	Z _S	Z_L
(MHz)	(Ω)	(Ω)
3100	0.9 - j4.3	5.3 – j1.6
3200	1.3 – j4.9	4.8 – j1.5
3300	1.7 – j5.5	4.6 – j1.9
3400	2.4 – j6.4	4.0 – j2.1
3500	4.1 – j6.9	4.0 – j2.1



7.3 Test circuit information

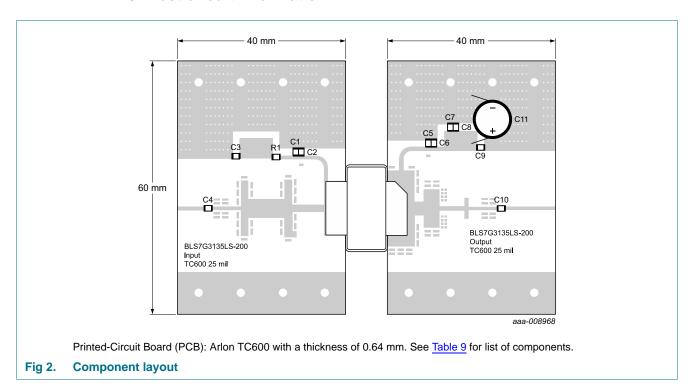


Table 9. List of components
See Figure 2 for component layout.

	<u> </u>			
Component	Description	Value		Remarks
C1, C4, C4, C10	multilayer ceramic chip capacitor	15 pF	<u>[1]</u>	ATC600F
C2, C5	multilayer ceramic chip capacitor	10 pF	[1]	ATC600F
C3, C9	multilayer ceramic chip capacitor	0.1 μF	[2]	TDK
C7	multilayer ceramic chip capacitor	1 μF	[3]	Murata
C8	multilayer ceramic chip capacitor	10 μF	[3]	Murata
C11	electrolytic capacitor	2200 μF, 63 V		
R1	chip resistor	9.1 Ω	[4]	SMD 0805

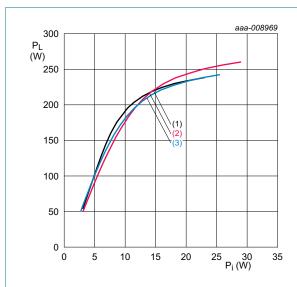
- [1] American Technical Ceramics type 600F or capacitor of same quality.
- [2] TDK or capacitor of same quality.
- [3] Murata or capacitor of same quality.
- [4] Vishay Dale or resistor of same quality.

BLS7G3135LS-200

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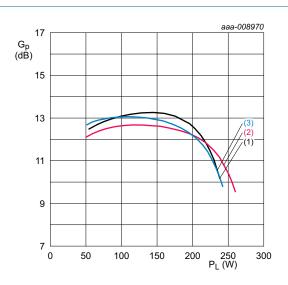
7.4 Graphical data



 V_{DS} = 32 V; I_{Dq} = 100 mA; δ = 10 %; t_p = 300 $\mu s.$

- (1) f = 3100 MHz
- (2) f = 3300 MHz
- (3) f = 3500 MHz

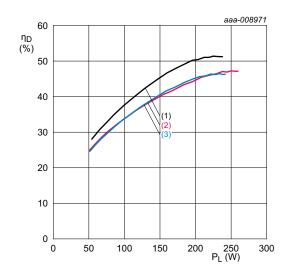
Fig 3. Output power as a function of input power; typical values



 V_{DS} = 32 V; I_{Dq} = 100 mA; δ = 10 %; t_p = 300 μ s.

- (1) f = 3100 MHz
- (2) f = 3300 MHz
- (3) f = 3500 MHz

Fig 4. Power gain as a function of output power; typical values



 V_{DS} = 32 V; I_{Dq} = 100 mA; δ = 10 %; t_p = 300 μs .

- (1) f = 3100 MHz
- (2) f = 3300 MHz
- (3) f = 3500 MHz

Fig 5. Drain efficiency as a function of output power; typical values

8. Package outline

Earless flanged ceramic package; 2 leads

SOT502B

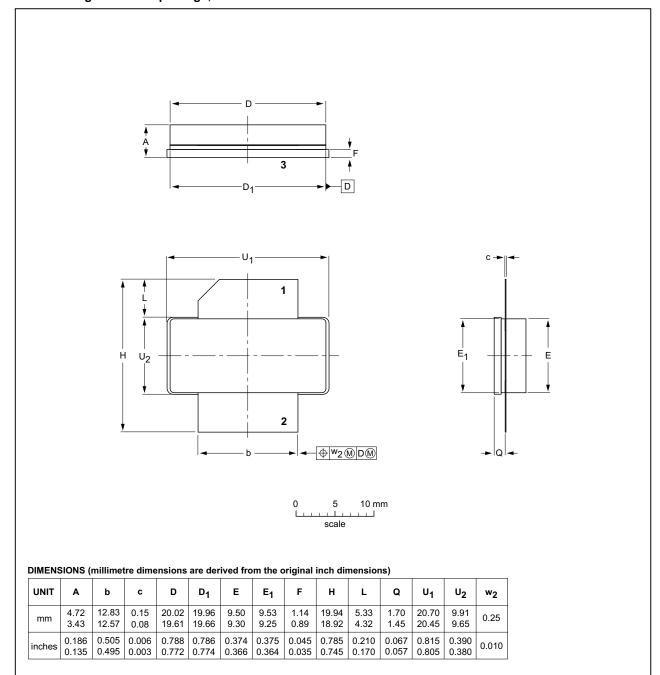


Fig 6. Package outline SOT502B

IEC

OUTLINE

VERSION

SOT502B

JEITA

REFERENCES

JEDEC

ISSUE DATE

07-05-09

12-05-02

EUROPEAN

PROJECTION

9. Handling information

CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Observe precautions for handling electrostatic sensitive devices.

Such precautions are described in the ANSI/ESD S20.20, IEC/ST 61340-5, JESD625-A or equivalent standards.

10. Abbreviations

Table 10. Abbreviations

Acronym	Description	
ESD	ElectroStatic Discharge	
LDMOS	aterally Diffused Metal-Oxide Semiconductor	
S-band	Short wave band	
SMD	Surface Mounted Device	
VSWR	Voltage Standing-Wave Ratio	

11. Revision history

Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BLS7G3135LS-200 v.2	20130923	Product data sheet	-	BLS7G3135LS-200 v.1
Modifications:	• Table 1 on p	page 1: table updated.		
	• Section 1.2	on page 1: section updated	d.	
	• Table 4 on page 2: table note added.			
	• <u>Table 5 on page 2</u> : table updated.			
	• <u>Table 6 on page 3</u> : table updated.			
	• <u>Table 7 on page 3</u> : table updated.			
	 Section 7 or 	n page 3: section added.		
BLS7G3135LS-200 v.1	20121009	Objective data sheet	-	-

12. Legal information

12.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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